

Notice of References Cited	Application/Control No. 10/578,676	Applicant(s)/Patent Under Reexamination TANEYA ET AL.	
	Examiner MARCOS BATISTA	Art Unit 4134	Page 1 of 1

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*	C	US-2004/0058715 A1	03-2004	Taniguchi et al.	455/566
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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